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# Test Report

## Specific Tests



**Reference: C10RAP05-10-2 - Version: 2.0**  
**Form: 06FOR10-18-1 – Version: 0.2**  
**Including 41 pages**

**Date: 23/06/2010**

**Product : JSC “LODVILA” plastic card**  
**Company : JSC “Lodvila”**  
**Address : Sėlių 3A,**  
**LT-08125 Vilnius,**  
**Lithuania**

**Dates of the session: from May 10 to June 23, 2010**

Owned by :	Approved by :

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Test results described in this report only relate to the samples tested.

## ***REVISION HISTORY***

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Date	Version	Author	Comments
11/06/2010	1.0	GBE	Initial Version
23/06/2010	2.0	GBE	Edde and Location of Contacts tests updated

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## **1 - TEST SITE INFORMATION**

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### **1.1 - Identification of the testing laboratory**

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The laboratory editing this report is:

**Silicomp Management**  
Immeuble Le Phoenix 1  
24, rue Emile Baudot  
91120 PALAISEAU - FRANCE  
Tel.: +33. (0) 1.64.53.95.00

The tests described in this report were conducted at the following premises:

**FIME Test Centre**  
8 rue Commodore J.H. HALLET  
14000 CAEN  
FRANCE  
Tel.: +33. (0) 2.31.44.08.07  
Fax: +33. (0) 2.31.44.44.77  
E-mail: fime@fime.com

### **1.2 - Test personnel**

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The following persons have collaborated to the preparation, execution or reporting of these tests:

L. Morcel, Test Operator  
G. Béhue, Test Operator  
Y. Briard, Test Operator  
Y. Linot, Project Manager

### **1.3 - FIME Operating Procedures**

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Procedures used for these tests are described in **PAQ Specific Tests, réf : 06PAQ10-18-1**.  
The PAQ version to be used is identified in PAQ chrono, *reference*: Chrono\_PAQ

### **1.4 - References**

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Tests performed according to the specifications described in:

- ISO/IEC 10373-1 'General Characteristics tests' from 15 December 1998.
- ISO/IEC 10373-3 'Integrated circuit(s) cards with contacts and related interface devices' from 15 February 2001.
- ISO/IEC 7810 'Physical characteristics' from 01 November 2003.
- ISO/IEC 7816-1 'Physical characteristics' from 15 October 1998.
- ISO/IEC 7816-2 'Dimensions and location of the contacts' from 01 March 1999.
- GIE Carte Bancaire 'Support Plastique' Version 3.1 from 04 April 2000.
- MIL STD 883 E 'Test Method Standard – Microcircuits'
- ANSI INCITS 322 – 2002 'Card Durability Test Methods'
- Mastercard CQM IQR v1.9D – 'Card Quality Management : Infrastructure Quality Requirements'

### **1.5 - Subcontractors**

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- **Test Toxicity**  
Name: SGS Multilab  
Address: 65, rue Ettore Bugatti, BP90014  
76801 Saint Etienne du Rouvray, France  
Tel.: 02 35 07 91 91  
Fax: 02 35 07 91 90
  
- **Test Salt Mist and Light Fastness**  
Name: SERCOVAM  
Address: 10, Chemin de Marticot, 33611 Cestas, France  
Tel.: 05 57 97 02 33  
Fax: 05 57 83 53 73
  
- **Test X-Ray**  
Name: SERMA Technologies  
Address: 30, Avenue Gustave Eiffel, 33608 Pessac, France  
Tel.: 05 57 26 08 88  
Fax: 05 57 26 08 98

## 2 - PROVIDER'S INFORMATION

### 2.1 - Card Provider Identification

The card provider that requested the tests described in this report is identified as:

Company : JSC “LODVILA”  
Address : Sėlių 3A,  
LT-08125 Vilnius,  
Lithuania

Contact.: Jurgis Rakstelis  
Tel.: (+370 5) 2790795  
Fax.: (+370 5) 2790893  
Email.: lodvila@lodvila.lt

### 2.2 - Cards Identification

First batch: The samples have been received on May 10, 2010.

Second batch: The samples have been received on June 22, 2010.

#### *Samples Identification :*

Item Description	Quantity	Identification
JSC LODVILA plastic card	200	1L422 to 200L422
JSC LODVILA plastic card	9	1L430 to 9L430

#### *Photo of the Tested Cards :*



### 3 - TEST RESULTS SUMMARY

The report concerns only the tested samples.

N°	Test Description	Part	Test Method	Nb of Card	Nb of Failure	Verdict
1	Dimensions of cards (thickness)	7810 § 5.1	10373-1 § 5.2	199	0	PASS
2	Dimensions of cards (Height & Width)	7810 § 5.1	10373-1 § 5.2	10	0	PASS
3	Dimensions of cards (Edge & Corners)	7810 § 5.1	10373-1 § 5.2	9	0	PASS
4	Bending stiffness	7810 § 8.1	10373-1 § 5.7	10	0	PASS
5	Toxicity	7810 § 8.3	EN 71-3	10	0	PASS
6A	Resistance to chemicals	7810 § 8.4	10373-1 § 5.4	16	0	PASS
6B	Salt Mist	7810 § 8.4	9227:1990	5	0	PASS
7	Card dimensional stability	7810 § 8.5	10373-1 § 5.5	10	0	PASS
8	Delamination (90°)	7810 § 8.8	10373-1 § 5.3	10	0	PASS
9	Adhesion or blocking	7810 § 8.9	10373-1 § 5.6	10	0	PASS
10	Opacity	7810 § 8.10	10373-1 § 5.10	10	0	PASS
11	Card Warpage	7810 § 8.11	10373-1 § 5.1	199	0	PASS
12	Ultraviolet Light	7816-1 § 4.2.1	10373-1 § 5.11	6	0	PASS
13	X-Rays	7816-1 § 4.2.2	10373-1 § 5.12	10	0	PASS
14	Surface profile of contacts	7816-1 § 4.2.3	10373-3 § 5.4	10	0	PASS
15	Mechanical Test	7816-1 § 4.2.4	-	10	0	PASS
16	Electrical resistance of contact	7816-1 § 4.2.5	10373-3 § 5.3	10	0	PASS
17	Static Electricity	7816-1 § 4.2.7	10373-3 § 5.2	10	0	PASS
18	Operating Temperature	7816-1 § 4.2.8	-	4	0	PASS
19	Dynamic Bending stress	7816-1 § 4.2.9	10373-1 § 5.8	10	0	PASS
20	Dynamc Torsional stress	7816-1 § 4.2.10	10373-1 § 5.9	10	0	PASS
21	Location of contacts	7816-2 § 4	10373-3 § 5.1	9	0	PASS
22	Light Fastness	ISO 105 A2	ISO 105 A2	5	0	PASS

#### **4 - DETAILED TESTS RESULTS**

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##### **COMMENTS :**

For most of the tests FIME verifies on one hand the visual aspect of the card and on the other hand the functionality of the microcircuit.

The visual aspect is checked by observing absence of :

- Initial detachment of the protection coat,
- Initial break,
- Failing of coloration,

The functionality of the microcircuit is checked by verifying if the microcircuit has survived the action of potentially destructive influence to the extent that :

- Any integrated circuit present on the card continues to show an Answer to Reset response after powering on all the contacts.

## Test N°1 – Dimensions of the cards (thickness)

1/4

### OBJECTIVE :

The purpose of this test is to measure the thickness of the card.

### REFERENCE :

ISO 10373-1 / ISO 7810 § 5.1.2

### TEST BENCH :

- A micrometer Mitutoyo:
  - Precision of the measure:  $\pm 3 \mu\text{m}$  (K=2)
  - Force of the measure: 3.5 N
- A load of  $2.20 \pm 0.01$  N.

### PROCEDURE :

Use the micrometer to measure the thickness of the card in the four quadrants. The measurements shall be made at locations on the card that do not include signature panels, magnetic stripes or contacts (integrated circuits cards), or any other raised area. The micrometer force shall be between 3.5N to 5.9N. Graphic shows repartition for quadrant n°1.

Quadrant 1	Quadrant 2
Quadrant 3	Quadrant 4

Disposition of the quadrants

### CRITERIA :

The thickness of the card shall be  $760 \mu\text{m} \pm 80 \mu\text{m}$ .

### RESULTS: (Cards tested : N°1 to 199L422)

Nb of Failure : 0 (6 measurements are in the uncertainty area of the micrometer)

Item	Quadrant N°1	Quadrant N°2	Quadrant N°3	Quadrant N°4
Mean ( $\mu\text{m}$ )	826	826	826	828
Max ( $\mu\text{m}$ )	840	839	842	843
Min ( $\mu\text{m}$ )	805	811	808	809
Standard Deviation ( $\mu\text{m}$ )	6.2	5.8	5.9	6.3

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°1 – Dimensions of the cards (thickness)

2/4

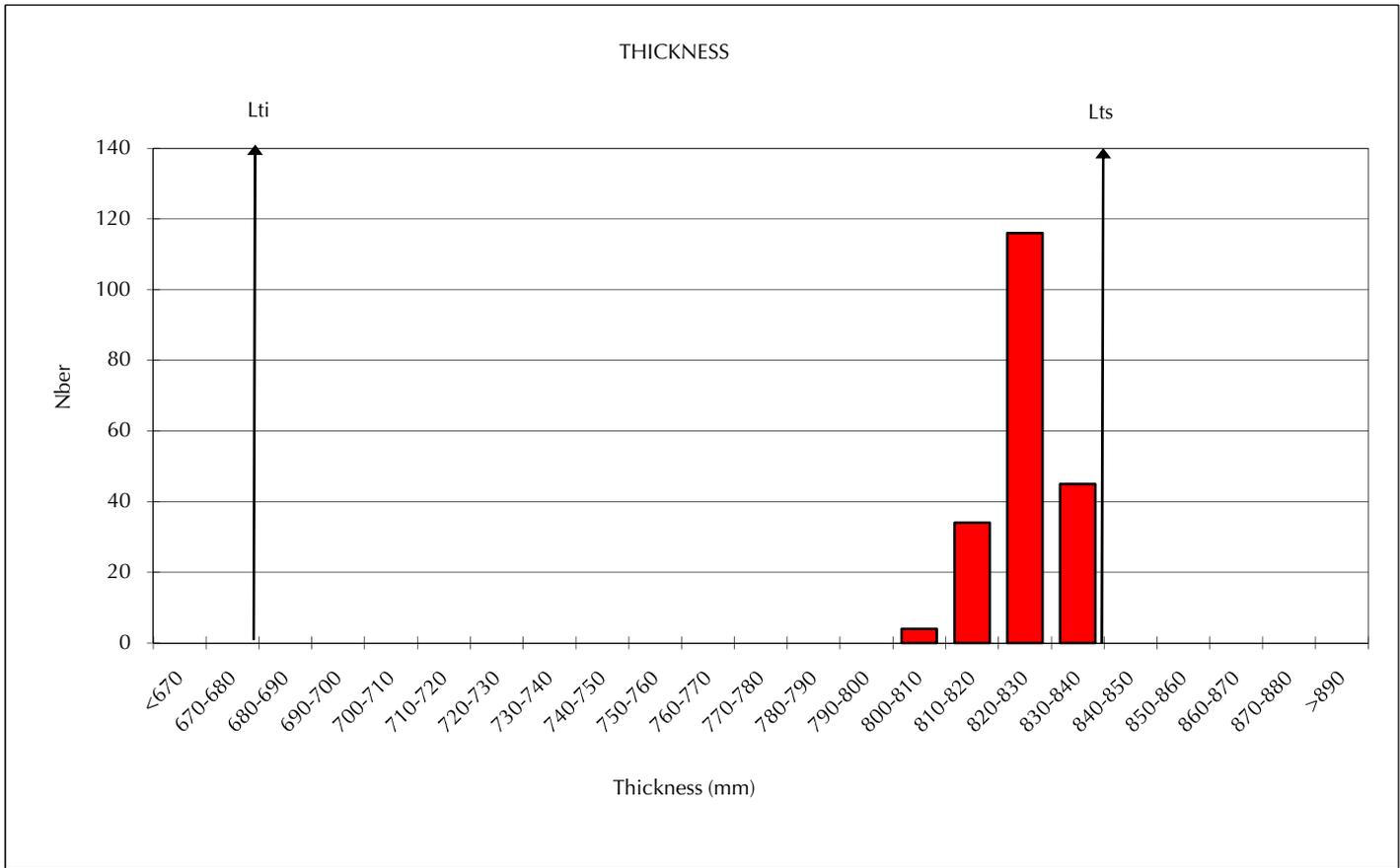
Card Nber	Quadrant N°1	Quadrant N°2	Quadrant N°3	Quadrant N°4	Card Nber	Quadrant N°1	Quadrant N°2	Quadrant N°3	Quadrant N°4
1	821	819	819	820	51	828	825	829	830
2	821	828	820	828	52	839	839	839	842
3	832	827	833	828	53	835	834	839	842
4	831	827	829	829	54	829	826	828	828
5	824	832	826	837	55	829	827	829	830
6	829	831	829	832	56	817	818	818	818
7	829	830	828	830	57	816	817	817	821
8	830	830	830	839	58	818	825	817	818
9	824	824	825	828	59	819	822	825	824
10	831	833	834	836	60	816	818	814	819
11	825	828	826	828	61	831	829	830	832
12	830	838	833	838	62	829	831	832	835
13	823	829	825	832	63	832	836	830	835
14	829	831	831	832	64	830	831	831	836
15	832	832	833	833	65	827	821	825	825
16	823	823	825	829	66	827	827	826	828
17	834	832	835	833	67	825	823	826	825
18	830	830	829	827	68	819	821	818	827
19	823	824	824	828	69	825	825	822	827
20	824	823	824	824	70	826	825	830	834
21	823	822	823	823	71	826	822	822	831
22	820	822	818	820	72	827	824	823	827
23	816	819	817	818	73	830	825	826	831
24	821	821	821	819	74	829	832	829	829
25	820	819	818	818	75	834	832	836	834
26	833	835	832	836	76	828	826	826	829
27	810	815	815	820	77	833	834	832	834
28	821	818	820	820	78	835	833	834	833
29	822	823	822	819	79	829	831	828	831
30	828	829	828	831	80	831	829	829	830
31	820	827	825	830	81	822	825	824	826
32	828	829	826	828	82	826	825	828	823
33	825	818	818	833	83	828	827	830	828
34	828	827	828	830	84	822	823	824	824
35	821	819	821	827	85	832	832	833	832
36	822	824	825	825	86	825	823	826	823
37	835	828	832	832	87	818	823	823	822
38	828	817	826	827	88	826	823	828	827
39	814	812	816	816	89	829	830	833	831
40	825	827	828	831	90	830	828	831	830
41	827	831	828	835	91	831	832	832	832
42	832	827	831	829	92	829	831	834	835
43	828	831	824	832	93	832	830	835	835
44	821	824	820	822	94	835	836	834	836
45	814	817	819	813	95	832	831	830	832
46	828	828	828	830	96	834	836	832	834
47	826	819	829	825	97	839	838	840	841
48	831	830	832	832	98	836	835	842	840
49	816	819	821	822	99	828	829	830	833
50	816	815	817	822	100	833	835	835	835

## Test N°1 – Dimensions of the cards (thickness)

3/4

Card Nber	Quadrant N°1	Quadrant N°2	Quadrant N°3	Quadrant N°4	Card Nber	Quadrant N°1	Quadrant N°2	Quadrant N°3	Quadrant N°4
101	819	814	820	809	151	827	829	826	830
102	828	825	827	829	152	829	825	827	831
103	834	834	833	835	153	838	818	831	833
104	826	826	829	827	154	831	829	832	833
105	840	836	834	834	155	829	828	830	831
106	832	834	837	836	156	829	823	831	829
107	827	824	826	825	157	823	825	821	829
108	824	828	822	826	158	832	827	832	825
109	825	824	825	828	159	828	828	830	829
110	818	824	821	825	160	829	832	821	828
111	812	811	816	812	161	830	831	826	824
112	824	819	821	820	162	824	827	826	829
113	833	831	830	836	163	821	821	825	824
114	825	824	826	823	164	826	822	825	824
115	832	831	830	835	165	824	824	827	829
116	830	831	829	833	166	826	828	828	830
117	831	832	832	833	167	832	832	829	829
118	831	831	832	833	168	832	832	833	834
119	820	820	821	827	169	826	826	820	822
120	826	826	827	829	170	828	832	829	836
121	831	832	832	833	171	816	817	811	810
122	833	835	837	841	172	805	814	811	814
123	827	827	825	829	173	818	822	821	822
124	823	826	827	824	174	820	825	825	823
125	821	820	821	830	175	814	815	817	820
126	823	824	825	824	176	810	812	808	810
127	822	824	825	823	177	809	812	809	810
128	825	824	826	828	178	816	819	814	820
129	819	827	820	820	179	815	820	818	819
130	828	830	829	826	180	817	819	819	818
131	829	830	830	833	181	818	820	817	822
132	826	820	830	825	182	824	819	825	825
133	826	821	825	827	183	822	822	825	822
134	830	827	830	827	184	822	823	823	832
135	830	828	829	828	185	825	827	822	824
136	830	828	832	829	186	827	826	825	828
137	832	829	829	826	187	830	827	824	821
138	828	829	827	833	188	829	832	828	828
139	827	828	828	829	189	825	824	830	827
140	818	818	820	824	190	813	813	820	822
141	821	823	821	821	191	828	832	830	843
142	828	824	832	826	192	821	828	826	832
143	824	823	828	826	193	829	833	828	834
144	825	825	825	826	194	832	830	831	835
145	817	819	823	824	195	832	833	828	828
146	814	818	814	820	196	828	835	830	836
147	820	825	818	828	197	831	834	827	832
148	816	821	828	832	198	831	829	833	832
149	824	821	823	827	199	828	833	826	837
150	829	823	829	820					

**Test N° – Dimensions of the cards (thickness)** 4/4



## Test N°2 – Dimensions of the cards (height & width)

1/2

### OBJECTIVE :

The purpose of this test is to measure the height and the width of the card.

### REFERENCE :

ISO 10373-1 / ISO 7810 5.1.1

### TEST BENCH :

- A profile projector NIKON.  
 Precision:  $+(4+L/25) \mu\text{m}$ ;  $-(4+L/50) \mu\text{m}$  with L in mm  
 Measure uncertainty :  $\pm 16 \mu\text{m}$
- A load of  $2.2 \text{ N} \pm 0.2 \text{ N}$

### PROCEDURE :

Place the sample card on the level horizontal rigid surface and flatten it under the  $2.2\text{N} \pm 0.2\text{N}$  load. Use the profile projector to measure the height and width of the card.

### CRITERIA :

All the points on the edges of the card in the finished state, except for the rounded corners, shall fall between two concentric, similarly aligned rectangles which are dimensioned as follows :

Unembossed card:

Outer rectangle:	Width : 85,72 mm	Height : 54,03 mm
Inner rectangle :	Width : 85,47 mm	Height : 53,92 mm

### RESULTS : (Cards tested : N°181 to 190L422)

Nb of Failure : 0

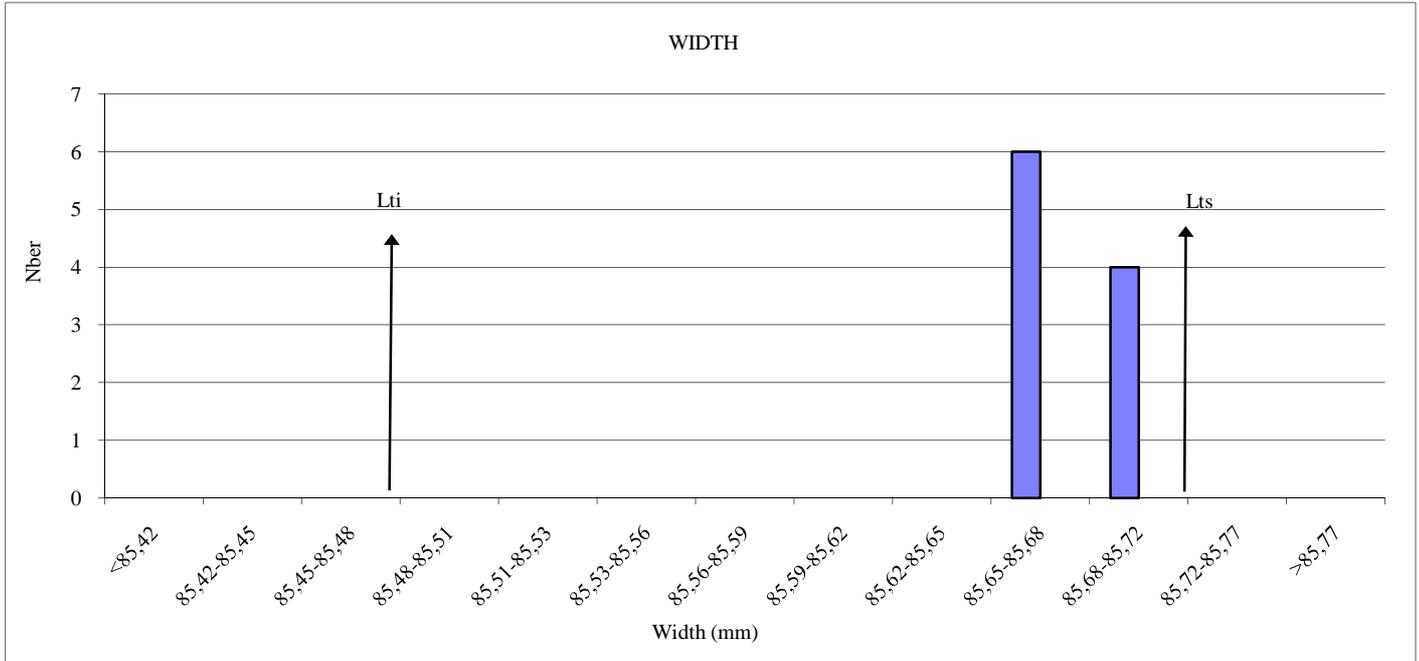
Card Nber	Width	Height
181	85,683	53,951
182	85,673	53,969
183	85,7	53,993
184	85,656	53,978
185	85,711	53,975
186	85,686	53,979
187	85,661	53,962
188	85,672	53,989
189	85,677	54,026
190	85,661	53,976

### OBSERVATIONS :

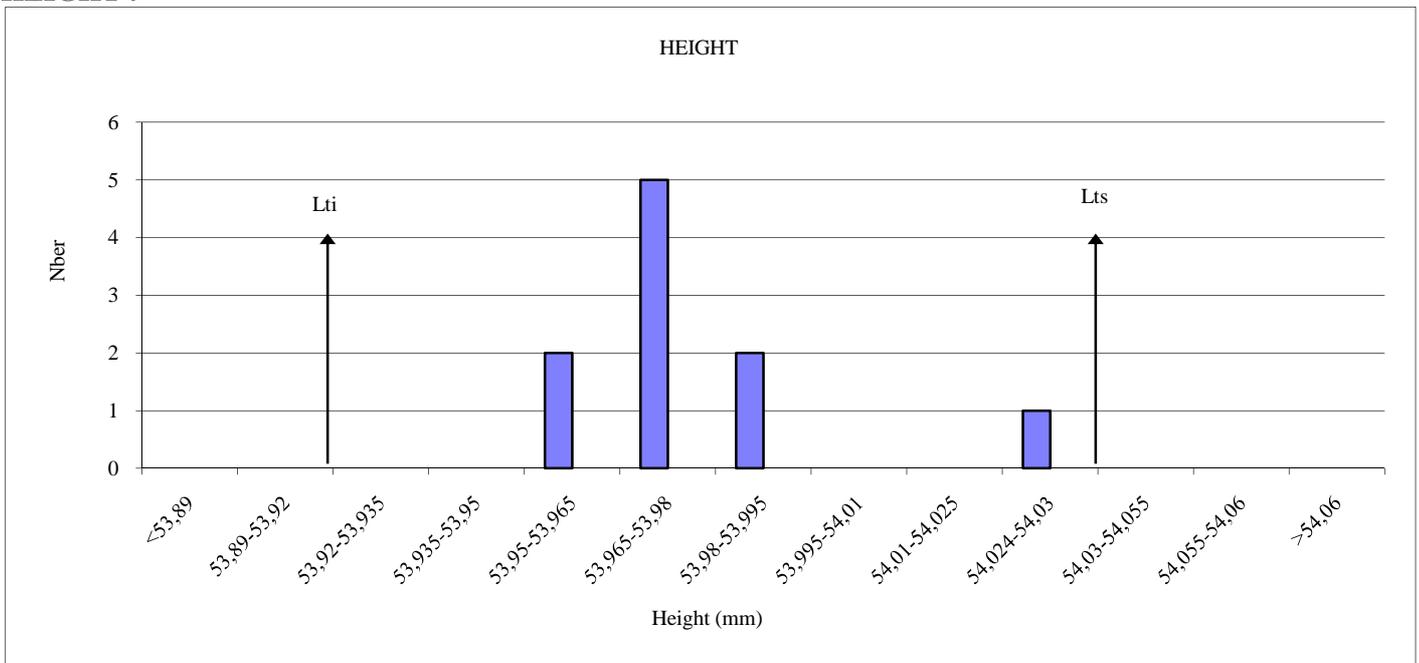
Tested samples are compliant with the specifications.

**Test N°2 – Dimensions of the cards (height & width)** 2/2

**WIDTH :**



**HEIGHT :**



## Test N°3 – Dimensions of the cards (edges & corners )

1/1

### OBJECTIVE :

The purpose of this test is to verify the compliance to the standard of the edges and corners of the card.

### REFERENCE :

ISO 10373-1 / ISO 7810 5.1.1 & 5.1.2

### TEST BENCH :

- Profile projector NIKON.  
Precision:  $+(4+L/25) \mu\text{m}$ ;  $-(4+L/50) \mu\text{m}$  with L in mm  
Measure uncertainty :  $\pm 16 \mu\text{m}$
- Corner template
- Load of  $2.2 \text{ N} \pm 0.2 \text{ N}$

### PROCEDURE :

Corner: Place the sample card on the level horizontal rigid surface and flatten it under the  $2.2\text{N} \pm 0.2\text{N}$  load. Place the corner template on the screen. Determine if each sample's corner fits between the minimum and maximum radius curves.

Edge: Place the sample card on the level horizontal rigid surface and flatten it under the  $2.2\text{N} \pm 0.2\text{N}$  load. On one edge, determine the edge limit and set the micrometer. Check the height of every burrs present on this edge. Repeat previous operations with the other edges.

### CRITERIA :

Card corners shall have a radius included between 2.88 mm and 3.48 mm.  
Edge burrs shall not exceed 0.08 mm above the card surface.

### RESULTS : (Cards tested: N°1 to 9L430)

Nber of Corner failure: 0  
Nber of Edge failure: 0

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°4 – Bending stiffness

1/1

### OBJECTIVE :

The purpose of this test is to determine whether the bending stiffness of a card test sample lies within the limits set by the base standard.

### SPECIFICATIONS :

ISO 7810 § 8.1 / ISO 10373-1 § 5.7

### TEST BENCH:

- A clamping device :  
 Measure uncertainty:  $\pm 0.5$  mm

### PROCEDURE :

Mount the sample card in the apparatus such that it is clamped along the entire left side, front surface upwards. Measure the h1. Apply a load equivalent to 0.7 N within 3 mm along the entire right side of the card for 1 min. Measure h2. Dismount the load and let the card return to its original position. After one minute, measure h3.

### CRITERIA :

The stiffness amplitude (h2-h1) shall be between :

- Minimum superior at 13 mm,
- Maximum inferior at 35 mm.

The sample card shall return within 1.5mm of its original position.

### RESULTS : (Cards tested : N°11 to 20L422)

Amplitude Min : 16 mm  
 Amplitude Max : 17 mm  
 Amplitude Mean : 17 mm  
 Nb of Failure : 0

Card N°	Deflection (mm)	H1 (cm)	H2 (cm)	H3 (cm)	Warpage (mm)	Verdict
11L422	17	17,4	15,7	17,3	1	PASS
12L422	17	17,5	15,8	17,4	1	PASS
13L422	17	17,4	15,7	17,4	0	PASS
14L422	17	17,4	15,7	17,3	1	PASS
15L422	17	17,5	15,8	17,5	0	PASS
16L422	17	17,4	15,7	17,3	1	PASS
17L422	17	17,5	15,8	17,5	0	PASS
18L422	17	17,5	15,8	17,5	0	PASS
19L422	17	17,5	15,8	17,4	1	PASS
20L422	16	17,4	15,8	17,4	0	PASS

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°5 – Toxicity

1/1

### OBJECTIVE :

The purpose of this test is to determine the toxicity of the card.

### REFERENCE :

ISO 7810 § 8.3 / EN 71-3 (Components migration)

### TEST BENCH :

- Sub-contractor equipment.

### PROCEDURE :

Proceed to sampling according to EN 71-3.

### CRITERIA :

Analysis results shall not show quantity superior to the maximum quantity defined below.

### RESULTS : (Cards tested : N°21 to 30L422)

Component	Antimony	Arsenic	Barium	Cadnium	Chromium	Lead	Mercury	Selenium
Maximum	60 mg/kg	25 mg/kg	1000 mg/kg	< 75 mg/kg	60 mg/kg	90 mg/kg	60 mg/kg	500 mg/kg
Measurement	<2.5 mg/Kg	<0.5 mg/Kg	<0.5 mg/Kg	<0.25 mg/Kg	0.4 mg/Kg	<2.5 mg/Kg	<0.3 mg/Kg	<0.5 mg/Kg

### OBSERVATIONS :

#### Test Sub-Contracted

Tested samples are compliant with the specification.

## Test N°6a – Resistance to chemicals

1/2

### OBJECTIVE :

The purpose of this test is to determine any adverse effects of a range of chemical contamination on a card test sample.

### REFERENCE :

ISO 7810 § 8.4 / ISO 10373-1 § 5.4

### TEST BENCH :

- A chronometer.
- A thermometer.

### Solutions :

- a) 5% salt water
- b) 5 % acetic acid water
- c) 5 % carbonated sodium water
- d) Aqueous solution containing 60 % of ethyl alcohol
- e) Sugared water (10 % solution)
- f) Fuel B (According to ISO 1817 :1985)
- g) Ethylene Glycol (50 % solution)
- h) Alkaline artificial perspiration
- i) Acid artificial perspiration

### Precision :

- ± 1 s for the short time.
- ± 1 min for the long time.

- A terminal TODOS Argos Mini II.

### PROCEDURE :

Expose the card to the appropriate short term or long term contamination described before. Immediately after removal from the solution, wash the card in distilled water and dry it with absorbent tissue. Perform any post-exposure measurements required by the base standard.

### Short term contamination :

The card is exposed during one minute to the solutions as follow, at a temperature between 20°C and 25 °C.

- a) 5% salt water (Card N°31 and 32)
- b) 5 % acetic acid water(Card N°33 and 34)
- c) 5 % carbonated sodium water (Card N°35 and 36)
- d) Aqueous solution containing 60 % of ethyl alcohol (Card N°37 and 38)
- e) Sugared water (10 % solution) (Card N°39 and 40)
- f) Fuel B (According to ISO 1817 :1985) (Card N°41 and 42)
- g) Ethylene Glycol (50 % solution) (Card N°43 and 44).

## Test N°6a – Resistance to chemicals

2/2

### Long term contamination:

Artificial perspiration. (Card N°45 to 46L422)

Two solutions are used: alkaline solution and acid solution. The card is exposed to each solution during 24 hours. Both solutions shall be prepared in accordance with ISO 105-E, 04-1978, « Textiles - Tests for colour fastness to perspiration ».

### CRITERIA :

The card shall resist degradation of its performance and appearance as a result of exposure to commonly encountered chemicals.

### RESULTATS : (Cards tested : N°31 to 46L422)

Nb of Aspect Failure :	0
Nb of Microcircuit Failure :	0

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°6b – Salt mist

1/1

### OBJECTIVE :

Verify the quality of the surface protection of the contacts on electrical resistance and impedance of contacts characteristics.

### REFERENCE :

ISO 7810 / ISO 10373-1 §5.4.1.2a / ISO 7816 / ISO 9227:1990

### TEST BENCH :

- A salt mist chamber : BS3
- A terminal TODOS Argos Mini II.

### PROCEDURE :

Put the test card sample in a test chamber with parameters set to :

- Concentration of sodium's chlorate : 5.0% +/- 0.5%
- Density of the solution :  $1030 < \rho (\text{Kg/m}^3) < 1040$
- Ph of the salt solution :  $6.50 < \text{Ph} < 7.20$ .

After 24 hours of testing in the salt mist the control of the parameters done :

- Ph of the salt solution : 7.10
- Density of the solution :  $\rho = 1034 \text{ Kg/m}^3$
- Pressure : 1.0 bars
- Testing temperature :  $35^\circ\text{C} \pm 1^\circ\text{C}$ .

### CRITERIA :

After the test check the aspect and the functionality of the test card sample.

### RESULTATS : (Cards tested : N°171 to 175L422)

Nb of Aspect Failure : 0  
Nb of Microcircuit Failure : 0

### OBSERVATIONS :

**Test Sub-Contracted**

Tested samples are compliant with the specifications.

## Test N°7 – Card dimensional stability and warpage with Temperature and Humidity exposure

1/2

### OBJECTIVE :

The purpose of this test is to establish whether the dimensions and flatness of a card test sample remain within the requirements of the base standard after exposure to the specified environmental temperature and humidity.

### SPECIFICATIONS :

ISO 10373-1 / ISO 7810 § 8.1.5

### TEST BENCH :

- Two climatic chambers VC2020 Votsch & Fryka.
  - Precision : A climatic chamber FRYKA:  $\pm 5^{\circ}\text{C}$
  - A climatic chamber VOTSCH:  $\pm 2^{\circ}\text{C}$
- A profile projector NIKON.
  - Precision :  $+(4+L/25) \mu\text{m}$ ;  $-(4+L/50) \mu\text{m}$  with L in mm
  - Measure uncertainty :  $\pm 16 \mu\text{m}$
- A micrometer Mitutoyo:
  - Resolution:  $1 \mu\text{m}$
  - Precision of the measure:  $\pm 3 \mu\text{m}$
  - Force of the measure:  $0.8 \text{ N}$
- A load of  $2.20 \pm 0.01 \text{ N}$

### PROCEDURE :

Place the sample card on a horizontal flat surface and expose it to each of the environments in the sequence listed below for 60 min :

#### Step 1 :

- Low temperature :  $-35^{\circ}\text{C} \pm 3\%$ ;
- Humidity:  $50\% \pm 5\%$ ;
- Delay: 1 Hour;
- Maximum transfer delay: 15 seconds;

#### Step 2 :

- High temperature :  $+50^{\circ}\text{C} \pm 3\%$ ;
- Humidity:  $50\% -3\% +2\%$ ;
- Delay: 1 Hour;
- Maximum transfer delay: 15 seconds;

Following each exposure in the sequence, return the sample card to the default test environment and retain it in this environment for 24 hours before measuring its dimensional stability and warpage.

### RESULTS : (Cards tested : N° 50 to 59L422)

Nb of Thickness Failure :	0 (2 measurements are in the uncertainty area of the micrometer)
Nb of Width Failure :	0
Nb of Height Failure :	0 (1 measurement is in the uncertainty area of the micrometer)
Nb of Card Warpage Failure :	0

## Test N°7 – Cards dimensional stability and warpage with Temperature and Humidity exposure

2/2

Before Test	N°	Thickness (µm)	Width (mm)	Height (mm)	Warpage
	50L422	824	85,72	54,005	0,836
	51L422	830	85,683	54,025	0,91
	52L422	840	85,712	54,014	0,843
	53L422	840	85,714	54,001	0,862
	54L422	827	85,688	53,997	0,924
	55L422	829	85,717	53,985	0,926
	56L422	818	85,645	54,024	0,939
	57L422	820	85,629	54,027	0,909
	58L422	823	85,617	54,004	0,97
59L422	824	85,712	53,994	0,826	

After Test	N°	Thickness (µm)	Width (mm)	Height (mm)	Warpage
	50L422	823	85,694	53,986	1,012
	51L422	830	85,655	54,01	1,116
	52L422	842	85,696	53,991	1,033
	53L422	842	85,689	53,977	1,091
	54L422	828	85,701	53,966	1,135
	55L422	829	85,676	53,976	1,149
	56L422	820	85,685	54,017	1,142
	57L422	822	85,672	54,04	1,14
	58L422	823	85,681	54,019	1,099
59L422	825	85,707	53,989	0,97	

Statistics	N°	Thickness (µm)	Width (mm)	Height (mm)
	50L422	0,12	0,04	0,04
	51L422	0	0,03	0,03
	52L422	0,24	0,02	0,04
	53L422	0,24	0,03	0,04
	54L422	0,12	0,02	0,06
	55L422	0	0,05	0,02
	56L422	0,24	0,05	0,01
	57L422	0,24	0,05	0,02
	58L422	0	0,07	0,03
59L422	0,12	0,01	0,01	

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°8 – Delamination (90°)

1/1

### OBJECTIVE:

The purpose of this test is to measure resistance to delamination in terms of the peel strength of projective over-laminates applied to a printed card test sample.

### REFERENCE:

ISO 7810 § 8.8 / ISO 10373-1 § 5.3

### TEST BENCH :

- A measuring device DY30.

### PROCEDURE :

Cut the card, or score through the layer, to produce sections of width  $10\text{mm} \pm 0.1\text{ mm}$  ( $0.39\text{ in} \pm 0.04\text{ in}$ ). Using a sharp knife, cut the layer back from the core approximately  $10\text{ mm}$  ( $0.4\text{ in}$ ) and apply the clamp or adhesive tape to the cut back edge of the layer and core. If the peeling angle cannot be kept at  $90^\circ$  during the measurement, attach the stabilising plate to the core in advance. Place the prepared specimen in the tensile tester fixture. The card shall be fixed on the apparatus. Operate the tensile tester according to the manufacturers instructions  $300\text{ mm/min}$  ( $11.8\text{ in/min}$ ) to determine the peel strength in Newton's per centimeters.

### CRITERIA :

The minimum peel strength on one millimeter is  $3,5\text{ N/cm}$ .

### RESULTS : (Cards tested : N°60 to 69L422)

Nb of Failure : 0

### OBSERVATIONS :

For all the cards test sample, it is impossible to prepare the cards for the test due to the adherence for the surface, The ISO standards says “a tearing of the overlay during the test signifies that the bond is stronger than the overlay, which is automatically deemed acceptable”.  
So the cards tested are compliant with the test specifications.



## Test N°10 –Opacity (IR Led method)

1/2

### OBJECTIVE:

The purpose of this test is to determine the opacity/light transmittance density over a spectral range of 400 nm to 1000 nm.

### REFERENCE :

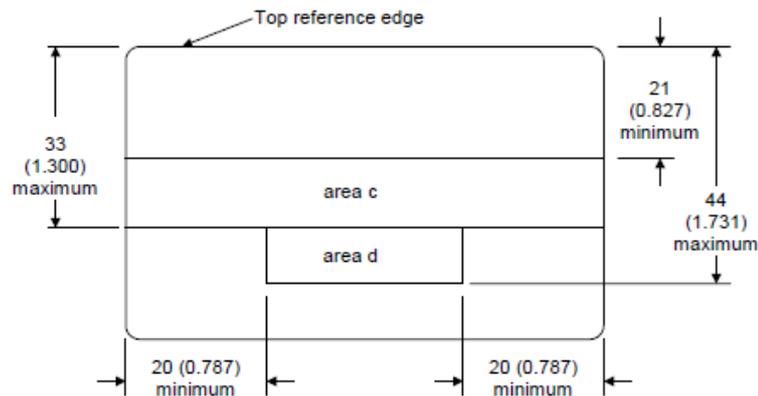
ISO 10373-1 / ISO 7810.

### TEST BENCH:

- Apparatus described in ISO 1.373-1 §5.10.2 with a LED at 860 nm and a LED at 950 nm
- reference : 5% densitometric screen (ORM 7810)

### PROCEDURE:

Two spots are chosen for measurements. Spots shall be anywhere on the card excepted in area ‘c’ and area ‘d’, and there shall be at least one spot per printed colour in each area measured.



### CRITERIA :

The light transmittance shall be greater than 1.3 from 450 nm to 950 nm and greater than 1.1 from 950 nm to 1000 nm.

### RESULTS : (In optical density) (Cards tested : N°80 to 89L422)

Nb of Failure : 0

Ratio of IR led current between sample and reference card

Item	860 nm led	950 nm led
BOCR (reference black)	0.0	0.0
ORM 7810 (reference material)	5.0	4.7

## Test N°10 – Opacity (IR Led method)

2/2

Item	860 nm led	950 nm led	Verdict (< 1)
80L422	0.0	0.0	<b>PASS</b>
81L422	0.0	0.0	<b>PASS</b>
82L422	0.0	0.0	<b>PASS</b>
83L422	0.0	0.0	<b>PASS</b>
84L422	0.0	0.0	<b>PASS</b>
85L422	0.0	0.0	<b>PASS</b>
86L422	0.0	0.0	<b>PASS</b>
87L422	0.0	0.0	<b>PASS</b>
88L422	0.0	0.0	<b>PASS</b>
89L422	0.0	0.0	<b>PASS</b>

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°11 – Card Warpage

1/2

### OBJECTIVE:

The purpose of this test is to measure degree of warpage of a card test sample.

### REFERENCE :

ISO 7810 § 8.11 / ISO 10373-1 § 5.1

### TEST BENCH :

- A profile projector NIKON.  
Precision: profile projector:  $+(4+L/25) \mu\text{m}; -(4+L/50) \mu\text{m}$  with L in mm  
Measure uncertainty :  $\pm 16 \mu\text{m}$
- A measuring device.

### PROCEDURE :

Place the card on the level rigid plate of the measuring apparatus. The card edges shall rest on the plate (warpage of the card in convex form to plate). Read the extent of warpage on the measuring device at the greatest point of the displacement, measured from the front surface of the card.

### CRITERIA :

The maximum warpage of a card shall be less than 1,5 mm.

### RESULTS : (Cards tested : N°1 to 199L422)

Nb of Failure :	0
Mean :	0.970 mm
Max :	1.159 mm
Min :	0.794 mm
Standard Deviation :	0.085 mm

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°11 – Card Warpage

2/2

Card Nber	Warpage						
1	0,962	51	1,029	101	1,02	151	0,93
2	0,972	52	0,917	102	0,829	152	1,082
3	0,855	53	0,962	103	0,918	153	1,064
4	1,013	54	0,963	104	0,816	154	1,056
5	1,139	55	0,997	105	0,971	155	1,011
6	0,916	56	1,074	106	0,978	156	0,939
7	1,008	57	1,057	107	0,892	157	0,944
8	0,931	58	1,106	108	0,899	158	0,952
9	1,035	59	0,905	109	0,847	159	0,929
10	0,993	60	0,923	110	1,03	160	0,929
11	1,098	61	0,942	111	0,91	161	0,93
12	0,935	62	0,984	112	1,073	162	0,923
13	1,046	63	0,954	113	0,892	163	0,908
14	1,05	64	0,961	114	0,995	164	0,927
15	0,93	65	1,086	115	0,927	165	0,925
16	1,041	66	1,088	116	0,967	166	1,097
17	0,913	67	1,089	117	0,954	167	0,943
18	0,958	68	1,042	118	0,889	168	0,919
19	0,941	69	1,019	119	0,905	169	0,911
20	0,929	70	0,827	120	0,912	170	1,049
21	0,932	71	1,134	121	0,894	171	0,929
22	0,809	72	1,093	122	0,938	172	0,86
23	0,802	73	1,016	123	0,915	173	0,833
24	0,884	74	1,005	124	1,095	174	0,828
25	0,834	75	0,868	125	1,073	175	0,84
26	0,826	76	0,947	126	1,033	176	0,804
27	0,812	77	0,887	127	1,096	177	0,815
28	0,816	78	0,99	128	1,039	178	0,825
29	1,02	79	0,976	129	1,085	179	0,831
30	0,84	80	0,939	130	1,059	180	0,849
31	1,026	81	0,956	131	0,908	181	0,886
32	1,058	82	1,031	132	0,954	182	1,038
33	1,086	83	1,076	133	0,939	183	1,04
34	0,916	84	1,069	134	1,082	184	1,117
35	0,927	85	1,066	135	0,876	185	0,901
36	1,02	86	0,964	136	1,073	186	0,974
37	0,942	87	1,072	137	1,02	187	1,033
38	1,126	88	0,929	138	1,107	188	1,031
39	0,941	89	1,076	139	0,898	189	0,912
40	1	90	1,003	140	0,936	190	0,94
41	0,99	91	1,016	141	0,947	191	1,065
42	0,932	92	1,088	142	1,043	192	1,075
43	1,037	93	0,907	143	1,026	193	1,08
44	0,977	94	0,91	144	0,868	194	1,052
45	1,159	95	0,912	145	0,984	195	1,063
46	0,922	96	0,927	146	0,896	196	1,014
47	1,083	97	0,794	147	1,062	197	1,023
48	0,962	98	0,849	148	1,017	198	1,079
49	0,988	99	0,817	149	0,937	199	0,988
50	0,947	100	0,915	150	0,93		

## Test N°12 – Ultraviolet Light

1/1

### OBJECTIVE:

The purpose of this test is to determine any adverse effects arising from exposure of a card test sample to ultraviolet light.

### REFERENCE :

7816-1 § 4.2.1 / ISO 10373-1 §5.11

### TEST BENCH :

- A test equipment with :
  - Power : 10 W
  - Wavelength : 2537 A°
  - Irradiation : 12 000 µW/cm<sup>2</sup>
- A terminal TODOS Argos Mini II.

### PROCEDURE :

Expose the test sample card to monochromatic light at a wavelength of 254 nm, ensuring that the test environment conditions are maintained. Expose the front of the card to a total energy of 0.15 Ws/mm<sup>2</sup>, and then repeat the process for the back of the card. The irradiance at the surface of the card shall correspond to an exposure time of 10 minutes to 30 minutes, according to the formula :

$$\text{Time (seconds)} = \frac{0.15 \text{ ( W.sec/mm}^2 \text{)}}{\text{Irradiation (}\mu\text{W/mm}^2\text{)}}$$

For example with irradiance of 0.12 mW/mm<sup>2</sup>, the exposure time is 20min, 50 sec.

### CRITERIA :

After the test check the aspect and the functionality of the test card sample.

### RESULTS : (Cards tested : N°90 to 96L422)

Nb of Aspect Failure : 0

Nb of Microcircuit Failure : 0

### OBSERVATIONS :

The exposure time is 20min, 50 sec.

Tested samples are compliant with the specifications.

## Test N°13 – X-Rays

1/1

### OBJECTIVE:

The purpose of this test is to determine any adverse effects arising from exposure of a card test sample to X-rays.

### REFERENCE :

ISO 7816-1 § 4.2.2 / ISO 10373-1 § 5.12

### TEST BENCH:

- A chamber for X-rays.
- A terminal TODOS Argos Mini II.

### PROCEDURE:

Expose both side of the card to X-ray radiation about 0.1 Gy by side with an acceleration voltage of 110 kV.

### CRITERIA :

After the test check the aspect and the functionality of the test card sample.

### RESULTS : (Cards tested : N°97 to 106L422)

Nb of Aspect Failure :	0
Nb of Microcircuit Failure :	0

### OBSERVATIONS :

**Test Sub-Contracted**

Tested samples are compliant with the specifications.

## Test N°14 – Surface profile of contacts

1/2

### OBJECTIVE :

The purpose of this test is to determine the difference in thickness between the ICC's contacts and the adjacent ICC surface.

### REFERENCE :

ISO 7816-1 § 4.2.3 / ISO 10373-3 § 5.4

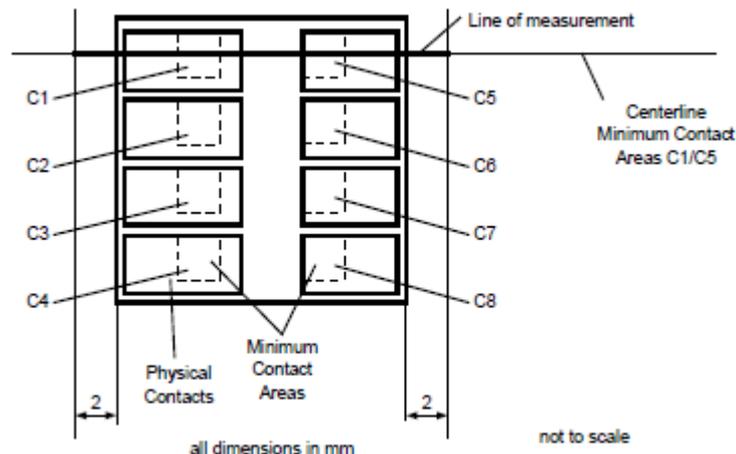
### TEST BENCH :

- A micrometer Mitutoyo:
  - Resolution: 1  $\mu\text{m}$
  - Precision of the measure:  $\pm 3 \mu\text{m}$
  - Force of the measure: 0.8 N

### PROCEDURE :

Apply the card test sample on a plate surface.

Construct a measurement line on the surface of the ICC along the centreline of the minimum contact areas C1 and C5, beginning and ending at a distance of 2mm of the metallized contact surface.



Measure the distance between the level rigid plate and the start and endpoint of the measurement line and calculate the arithmetic average of the two distances, subsequently called 'base thickness'.

Determine the minimum and maximum distance between the level rigid plate and all points on the surface of the ICC along the measurement line.

Calculate the difference between the base thickness and the minimum and the maximum distance determined previously.

Repeat for the centerlines of the contacts C2 and C6, C3 and C7 and, if present, C4 and C8.

### CRITERIA :

The difference between the body card and the contacts shall be inferior to 0.10mm.

## Test N°14 – Surface Profile of Contacts

2/2

### RESULTS : (Cards tested : N°107 to 116L422)

Nb of Failure : 0

Card N°	C1 – C5		C2 – C6		C3 – C7		C4 – C8	
	min	max	min	max	min	max	min	max
107L422	-53	-36	-69	-47	-64	-59	-51	-41
108L422	-69	-44	-97	-55	-97	-52	-51	-50
109L422	-67	-55	-83	-63	-70	-67	-44	-39
110L422	-53	-37	-75	-54	-68	-58	-39	-37
111L422	-51	-49	-63	-58	-69	-57	-28	-26
112L422	-52	-21	-51	-30	-52	-36	-38	-23
113L422	-83	-77	-82	-74	-89	-69	-41	-36
114L422	-58	-50	-66	-57	-66	-59	-41	-33
115L422	-69	-65	-87	-80	-100	-86	-68	-44
116L422	-70	-61	-69	-59	-70	-59	-62	-51

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°15 – Mechanical test

1/1

### OBJECTIVE :

The purpose of this test is to verify the behaviour of the card to the stockage and the handling.

### REFERENCE :

ISO7816-1 § 4.2.4

### TEST BENCH :

- A tool DY30.
- A terminal TODOS Argos Mini II.

### PROCEDURE :

- The embedded card (module side up) is positioned on a plate
- Determine the center of chip module
- Apply a force of 1.5N to the center of IC module (front side) for 1 minute.

### CRITERIA :

After the test check the aspect and the functionality of the test card sample.

### RESULTS : (Cards tested : N°117 to 126L422)

Nb of Failure : 0

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°16 – Electrical surface resistance of contacts

1/1

### OBJECTIVE :

The purpose of this test is to measure the electrical resistance between card-contact surface and card-connector contacts using a test card connector.

### REFERENCE :

ISO 10373-3 / ISO7816-1.

### TEST BENCH :

- One HP 34401 A.
- A terminal TODOS Argos Mini II.

### PROCEDURE :

Apply the two test probes to the card contact with a force of 0.5N +/-0.1N. The applied voltage shall not exceed the voltage drop caused by the maximum permitted test current across the maximum resistance. Measure the contact resistance and impedance by the voltage drop across two connections in series. Perform the test for each minimum rectangular surface area.

### CRITERIA :

The measurement of resistance on each contact shall be inferior to 500 mΩ.

### RESULTS : (In mΩ) (Cards tested : N°127 to 136L422)

Nb of Failure : 0

Card N°	C1	C2	C3	C4	C5	C6	C7	C8
127L422	54	59	57	63	58	56	73	52
128L422	61	81	64	78	63	65	63	74
129L422	62	63	64	62	57	63	65	70
130L422	53	62	65	55	52	55	50	57
131L422	64	63	60	62	54	56	55	61
132L422	64	66	68	60	57	59	69	61
133L422	60	52	59	51	56	59	62	60
134L422	60	75	65	61	54	51	57	70
135L422	63	53	62	64	64	60	59	61
136L422	63	55	60	51	52	53	57	63

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°17 – Static Electricity

1/1

### OBJECTIVE :

The purpose of this test is to determine any adverse effects of a electrostatic discharge on the component.

### REFERENCE :

ISO7816-1 § 4.2.7 / ISO 10373-3 § 5.2

### TEST BENCH :

- A static discharge simulator.
- A terminal TODOS Argos Mini II.

### PROCEDURE :

A discharge with a capacity of 100 pF is sent behind a resistor of 1500 Ohms. This discharge is successively sent on each contact of the card with a normal and inverse polarity. The tension of discharge is 4000 V. The time between each pulse must be set to 5 seconds minimum.

### CRITERIA :

After the test check the aspect and the functionality of the test card sample.

### RESULTS : (Cards tested : N°137 to 146L422)

Nb of Aspect Failure :	0
Nb of Microcircuit Failure :	0

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°18 – Operating temperature

1/1

### OBJECTIVE:

The purpose of this test is to check that the samples are operating as intended when submitted to an ambient temperature ranging from 0°C to 50°C.

### REFERENCE :

ISO 10373-6 / ISO 14443-1 §4.3.9.

### TEST BENCH:

- Climatic chamber: 02/03
  - Brand: SERVATHIN
  - Model or Type: SAPRATIN
  - Serial Number: 95/20793
  - Certificate of calibration: 1-1597 21/05/2008
  
- A terminal TODOS Argos Mini II.

### PROCEDURE:

The PICC under test and a terminal are placed under a temperature during 30 minutes. The functionality of the sample is then checked, within the climate chamber, by verifying the answer to ATR. The ambient temperatures of the thermal chamber verified are 0°C, 25°C and 50°C.

### CRITERIA :

After the test check the aspect and the functionality of the test card sample.

### RESULTS : (Cards tested : N°147 to 150L422)

Nb of Aspect Failure : 0  
Nb of Microcircuit Failure : 0

### OBSERVATIONS :

Tested samples are compliant with the specifications.

## Test N°19 – Dynamic bending stress

1/1

### OBJECTIVE:

The purpose of this test is to determine any adverse mechanical or functional effects of bending stress in a card test sample.

### REFERENCE :

ISO 7816-1 § 4.2.9 / ISO 10373-1 §5.8

### TEST BENCH :

- A test machine for unilateral bending Cybernetix.  
Precision : Flexion Amplitude:  $\pm 1$  mm  
Flexion Frequency:  $\pm 0.05$  Hz
- A terminal TODOS Argos Mini II.

### PROCEDURE :

Place the card test sample between the jaws of the test machine, positioned such that the bend occurs by curvature of the width. Apply one quarter the total number of bendings specified by the base standard or, if no such number is specified, 250 bendings.

Reposition the card such that the opposite face of the card is uppermost but the bend still occurs by curvature of the width. Apply the same number of bendings as before.

Reposition the card and reset the test machine such that the same face of the card is uppermost but the bend still occurs by curvature of the height. Apply the same number of bendings as before.

Reposition the card such that the opposite face of the card is uppermost but the bend still occurs by curvature of the height. Apply the same number of bendings as before.

### CRITERIA :

After the test check the aspect and the functionality of the test card sample.

### RESULTS : (Cards tested : N°151 to 160L422)

Nb of Aspect Failure : 0  
Nb of Microcircuit Failure : 0

### OBSERVATIONS :

Tested samples are compliant with the specifications.



## Test N°21 – Location of contacts

1/1

### OBJECTIVE :

The purpose of this test is to measure the location of the contacts on the card.

### REFERENCE :

ISO 7816-2 § 4 / ISO 10373-3 §5.1

### TEST BENCH :

- A profil projector NIKON  
 Precision:  $+(4+L/25) \mu\text{m}; -(4+L/50) \mu\text{m}$ , with L in mm  
 Measure uncertainty :  $\pm 16 \mu\text{m}$
- A tracing at the minimum dimensions.
- A load of  $2.2 \text{ N} \pm 0.2 \text{ N}$

### PROCEDURE :

Place the card to be tested, contact side up, on a flat hard surface. The card shall be held down by a load of  $2.2\text{N} \pm 0.2\text{N}$ .

Verify that the contacts are placed in the tracing minimum dimensions.

### CRITERIA :

Contact	A	B	C	D
C1	10.25	12.25	19.23	20.93
C2	10.25	12.25	21.77	23.47
C3	10.25	12.25	24.31	26.01
C4	10.25	12.25	26.85	28.55
C5	17.87	19.87	19.23	20.93
C6	17.87	19.87	21.77	23.47
C7	17.87	19.87	24.31	26.01
C8	17.87	19.87	26.85	28.55

A and C are the maximum values, B and D are the minimum values.

### RESULTS : (Cards tested : N°1 to 9L430)

Nb of Failure : 0

### OBSERVATIONS :

Tested samples are compliant with the specifications.

<b>Test N°22 –Light fastness</b>	<b>1/2</b>
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**OBJECTIVE :**

Verify the resistance of the card body to the exposure to a light source.

**REFERENCE :**

ISO 105-B02 (09-94) / DIN54004 Method 2.

**TEST BENCH :**

- A XENOTEST 150S.

**PROCEDURE :**

The cards are placed in a test chamber. They are exposed to the light source (Xenon Arc) during a period of 168 hours. In same time that the cards, a blue scale is placed in the chamber, this one is constituted with four talon N°4, N°5, N°6 and N°7. After the 168 hours, the evaluation of the colour is made by the way of a chamber which simulate the day light.

**CRITERIA :**

The degradation of the cards are compared to the grey scale (method ISO 105 A2) and to the blue scale (method NFG 07 012.2). Blue scale index shall be superior or equal to 3.

**RESULTS : (Cards tested : N°176 to 180L422)**

N°	Location	Cotation Grey scale	Cotation Blue scale	Observations - Aspect
176L422	Blue Arrow	5	>4	<b>PASS</b>
	Chip	5	>4	<b>PASS</b>
	Green Background	5	>4	<b>PASS</b>
	Yellow Background	5	>4	<b>PASS</b>
177L422	Blue Arrow	5	>4	<b>PASS</b>
	Chip	5	>4	<b>PASS</b>
	Green Background	5	>4	<b>PASS</b>
	Yellow Background	5	>4	<b>PASS</b>
178L422	Blue Arrow	5	>4	<b>PASS</b>
	Chip	5	>4	<b>PASS</b>
	Green Background	5	>4	<b>PASS</b>
	Yellow Background	5	>4	<b>PASS</b>

## Test N°22 – Light fastness

2/2

N°	Location	Cotation Grey scale	Cotation Blue scale	Observations - Aspect	
179L422	Blue “UTO” logo	4/5	4	PASS	
	Red “UTO” logo	5	>4	PASS	
	Blue printings	4/5	4	PASS	
	Hologram	5	>4	PASS	
	Lodvila logo	4/5	4	PASS	
	Yellow area				
	Lodvila logo	4/5	4	PASS	
	White area				
	Lodvila logo	5	>4	PASS	
	Green & Blue areas				
	Yellow background	4/5	4	PASS	
	Green background	5	>4	PASS	
	180L422	Blue “UTO” logo	4/5	4	PASS
		Red “UTO” logo	5	4	PASS
Blue printings		4/5	>4	PASS	
Hologram		5	4	PASS	
Lodvila logo		4/5	>4	PASS	
Yellow area					
Lodvila logo		4/5	4	PASS	
White area					
Lodvila logo		5	>4	PASS	
Green & Blue areas					
Yellow background		4/5	4	PASS	
Green background		5	>4	PASS	

Tested samples are compliant with the specifications.

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